

Form PTO 1449 (Modified)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY DOCKET NO. 292752US0PCT		SERIAL NO. 10/583,558	
LIST OF REFERENCES CITED BY APPLICANT				APPLICANT Naoki HOSOYA, et al.			
				FILING DATE June 19, 2006		GROUP 1761	
U.S. PATENT DOCUMENTS							
EXAMINER INITIAL	AA	DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
	AB						
	AC						
	AD						
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FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION YES NO		
VII ↓	AO	60-156614	08/16/85	Japan (w/English Abstract)		XX	
	AP	3-133928	06/07/91	Japan (Equivalent to EP 0 423 419, attached)			
	AQ	0 423 419	04/24/91	Europe			
	AR	2002-142677	05/21/02	Japan (w/English Abstract)		XX	
	AS	06-298930	11/19/96	Japan (w/English Abstract)		XX	
	AT	08-109178	04/30/98	Japan (w/English Abstract)		XX	
	AU	3378577	12/06/02	Japan (w/English Abstract)		XX	
	AV						
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)							
	AW						
	AX						
	AY						
	AZ						
					<input type="checkbox"/> Additional References sheet(s) attached		
Examiner <u>Niren Thakur/ (10/16/2007)</u>					Date Considered <u>10/16/2007</u>		
*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							

ATTY DOCKET NO.
292752US0PCT

SHEET 1 OF 1

SERIAL NO.
10/583,558

LIST OF REFERENCES CITED BY APPLICANT

APPLICANT
Masaki IWASAKI, et al.FILING DATE
June 19, 2006

GROUP

U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
	AA						
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FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION	
					YES	NO
NT/	AO	5-168407	07/02/1993	Japan (with English abstract)		X
NT/	AP	3-228667	10/09/1991	Japan (with English abstract)		X
	AQ					
	AR					
	AS					
	AT					
	AU					
	AV					

OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)

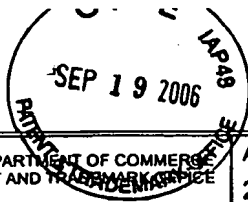
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☐ Additional References sheet(s) attached

Examiner Viren Thakur/ (10/16/2007)

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EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
NT/	AA	2006 0099318	05-11-06	IWASAKI, Masaki et al.			
NT/	AB	2005 0129829	06-16-05	HOSOYA, Naoki et al.			
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FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION	
					YES	NO
NT/	AO	2003 169641	06-17-03	JP (English abstract only)		NO
↓	AP	10 501407	02-10-98	JP (English abstract only and equivalent of US 5 464 619)		NO
	AQ	2003 169603	06-17-03	JP (English abstract only and equivalent of US 2003 77374)		NO
↓	AR	06 142405	05-24-94	JP (English abstract only)		NO
	AS	2003 259806	09-16-03	JP (English abstract only)		NO
	AT					
	AU					
	AV					

OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)

	AW	
	AX	
	AY	
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